Specifications

Drawing No.	UKY1C-H1-14053-00[37] 1/10
Issued Date.	Jan,17,2014

TO: KED USA

Note: In case of specification change, KYOCERA Part Number also will be changed.

Product Name	Quartz Crystal
Product Model	CX2016DB
Frequency	27000kHz
Customer Part Number	-
Customer Specification Number	-
KYOCERA Part Number	CX2016DB27000H0FLFC1
Remarks Pb-Free, RoHS Comp	bliant, MSL 1

Customer Acceptance

Accept Signature	Approved Date	
	Department	
	Person in charge	

Seller KYOCERA Corporation

6 Takeda Tobadono-cho, Fushimi-ku, Kyoto 612-8501 Japan TEL. No. 075-604-3500 FAX. No. 075-604-3501

Manufacturer KYOCERA Crystal Device Corporation

5850, Higashine-Koh, Higashine-Shi, Yamagata 999-3701 Japan TEL. No. 0237-43-5611 FAX. No. 0237-43-5615

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Crystal Units Engineering Section Crystal Units Division	A. Kikuchi	Y.Takahashi	T. Nitoube	Y. Kikuchi

Drawing No.	UKY1C-H1-14053-00[37] 2/10
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Revision History

Rev.No.	Description of revise	Date	Approved by	Checked by	lssued by
1	First Edition	Jan,17,2014	Y.Takahashi	T. Nitoube	Y. Kikuchi

1. APPLICATION

This specification sheet is applied to quartz crystal "CX2016DB"

2. KYOCERA PART NUMBER

CX2016DB27000H0FLFC1

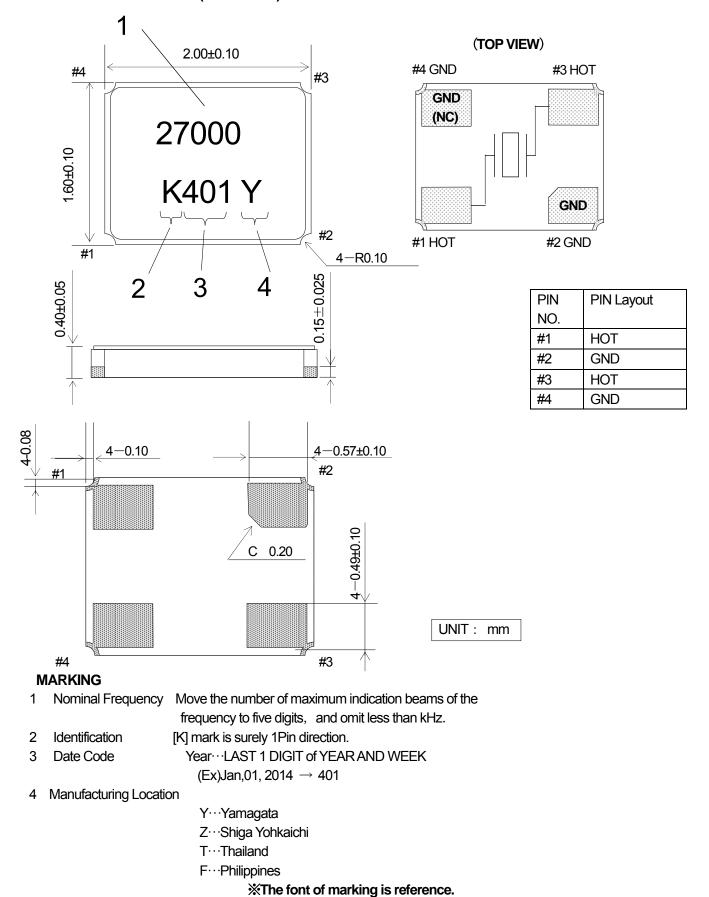
3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature	Topr	-30~+85	C°	
Storage Temperature range	Tstg	-40~+85	C°	

4. CHARACTERISTICS

ELECTRICAL CHARACTERISTICS

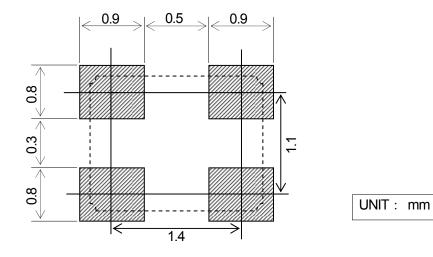
Items		Electrical Specification			Test Condition	Remarks	
	SYMB.	Min	Тур.	Max	Unit		
Mode of Vibration		F	undament	al			
Nominal Frequency	F0		27		MHz		
Nominal Temperature	T _{NOM}		+30		°C		
Load Capacitance	CL		12.0		pF	Saunders(S&A) Network Analyzer 250B	
Frequency Tolerance	df/F	-10.0		+10.0		+30±3°C	
Frequency Temperature Characteristics	df/F	-10.0		+10.0	PPM	-30∼+85°C	
Frequency Aging Rate		-1.0		+1.0		1 year	+30±3°C
Equivalent Series Resistance	ESR			80	Ω		
Drive Level	Pd	0.01		100	μW		
Insulation Resistance	IR	500			MΩ	100V(DC)	



5. APPEARANCES, PHYSICAL DIMENSION OUTLINE DIMENSION (not to scale)

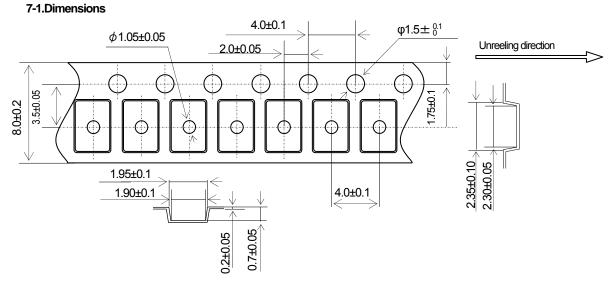
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KBS-5079E

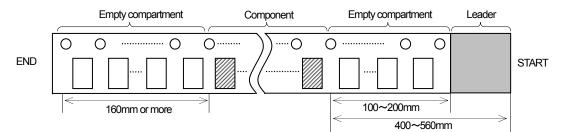


6. RECOMMENDED LAND PATTERN (not to scale)

7. TAPING&REEL



7-2.Leader and trailer tape



7-3.Direction (The direction shall be seen from the top cover tape side)



7-4.Specification

- 1. Material of the carrier tape shall be polystyrene or A-PET (ESD).
- 2. Material of the seal tape shall be polyester (ESD).
- 3. The seal tape shall not cover the sprocket holes. And not protrude from the carrier tape.
- 4. Tensile strength of the tape: 10N or more.
- 5. The R of the corner without designation is 0.2RMAX.
- 6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
- 7. Cumulative pitch tolerance of "P_0" shall be \pm 0.2mm at 10 pitches.
- 8. Suppose that it unifies as shown in the above-mentioned figure to the directivity of printing in an embossing tape.
- 9. Peeling force of the seal tape: 0.1 to 1.0N.
- 10. The component can fall headlong naturally from taping in the environment, such dry conditions, when this

components were transferred to, cover was removed and the component was moved upside down.

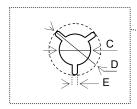
Cover tape 165° 180 Career tape

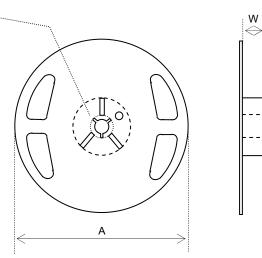
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В

7-5.Reel Specification





In the case of φ 180 Reel (3,000 pcs max, every 1,000 pcs)

Symbol	A	В	С	D
Dimension	φ180 +0/-3	φ60 +1/-0	φ13±0.2	φ21±0.8
Symbol	E	W	t	
Dimension	2.0±0.5	9±1	2.0±0.5	

(Unit:mm)

In the case of φ 330 Reel (12,000 pcs max, every 1,000 pcs)

Symbol	А	В	С	D
Dimension	φ330±2.0	φ100±1.0	φ13±0.2	φ21±0.8
Symbol	E	W	t	
Dimension	2.0±0.5	9.5±0.5	2.2±0.1	

(Unit:mm)

8.Enviromental requirements

After follo	\pm 10 $ imes$ 10 $^{-6}$	
And CI,	$\pm 20\%$ or 5 Ω of large value.	

8.1	Resistance to Shock	Test condition Natural dropped from height 100cm onto hard wood board in 3 times
8.2	Resistance to Vibration	Test conditionfrequency: 10 - 55 - 10 HzAmplitude: 1.5mmCycle time: 15 minutesDirection: X,Y,Z (3direction),2 h each.
8.3	Resistance to Heat	Test condition The quartz crystal unit shall be stored at a temperature of +85±2°C for 500 h. Then it shal be subjected to standard atmospheric conditions for 1 h ,after whichi measurement shall be made.
8.4	Resistance to Cold	Test condition The quartz crystal unit shall be stored at a temperature of $-40\pm2^{\circ}$ C for 500 h. Then it shal be subjected to standard atmospheric conditions for 1 h ,after whichi measurement shall be made.
8.5	Thermal Shock	Test condition The quartz crystal unit shall be subjected to 500 succesive change of temperature cycles , each as shown in table below, Then it shall be subjected to standard atmospheric conditions for 1h, after which measurements shall be made. Cycle $:-40\pm2^{\circ}$ C (30min.) to $+25\pm2^{\circ}$ C (5min.) to $+85\pm2^{\circ}$ C (30min.) to $+25\pm2^{\circ}$ C (5min.)

8.6 Resistance to Moisture	Test condition The quartz crystal unit shall be stored at a temperature of +60±2°C wich relative humidity of 90% to 95% for 240 h. Then it shall be subjected to standard atmospheric conditions for 1h, after which measurements shall be made

8.7 Soldering condition

1.) Material of solder

Kind … lead free solder paste

Melting point ··· +220±5°C

2.) Reflow temp.profile

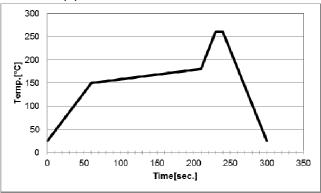
	Temp [°C]	Time[sec]
Preheating	+150 to +180	150 (typ.)
Peak	+260±5	10 (max.)
Total	—	300 (max.)

Frequency shift : ± 2 ppm

3.) Hand Soldering +350°C 3 sec MAX

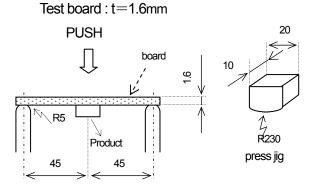
4.) Reflow Times 2 times

Reflow temp.profile



8.8 Intensity for bending in circuit board

Solder this product in center of the circuit board of $40 \text{mm} \times 100 \text{mm}$, and add the deflection of 3mm as the bottom figure.



UNIT : mm

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9. Cautions for use

(1) Soldering in mounting

In case of Solder paste and conductive glue contact product lid or product side face exception for product terminal it's possible to influence product characteristics.

- Please be careful above contents.
- (2) Automatic mounting machine use

Please use after affirmation that select the mounting machine model with a shock small if possible in the case of use of an automatic mounting machine, and it does not have breakage. There is a risk of a crystal oscillating child's breakage occurring and not functioning normally by too much shock etc.

(3) Conformity of a circuit

In case of use of an oscillation circuit, please insert in a crystal oscillating child in series resistance 5 times as many as the standard value of equivalent in-series resistance, and confirm oscillating. Please remove resistance which inserted after the notes above-mentioned examination in the crystal oscillating child in series, and use it.

10.Storage conditions

Storage at prolonged high temperature or low temperature and the storage by high humidity cause degradation of frequency accuracy, and degradation of soldering nature. Storage is performed at the temperature of +18 to +30°C, and the humidity of 20 to 70 % in the state of packing, and a term is 6 months.

11. Manufacturing location

Kyocera Crystal Device Corporation Kyocera Crystal Device Corporation Shiga Yohkaichi Plant Kyocera Crystal Device (Thailand) Co., Ltd Kyocera Crystal Device Philippines, Inc.

12. Quality Assurance

Kyocera Crystal Device Quality Assurance Division

13. Quality guarantee

When the failure by the responsibility of our company occurs clearly after delivery within 1 year, a substitute article etc. is appropriated gratuitously and this is guaranteed. However, when passing 1 year after delivery, there is a case where I am allowed to consider as onerous repair after both consultation.

14. Others

When any questions and opinions are in the written matter of these delivery specifications, I will ask connection of you from the company issue day within 45 days. In a connection no case, a written matter is consented to it and employed within a term.